

Design for Manufacturability in Lead Free Wave Solder Process

Ramon Mendez

Paper presented by **Craig Hamilton**

Celestica

Calle Octava # 102 Parque Industrial Monterrey

Apodaca - Nuevo Leon - 66600

Mexico

+52 81 8156 1500 ext 2099

rmendez@celestica.com

EXECUTIVE SUMMARY

The recent use of lead free alloys has made the wave solder process more challenging in terms of achieving acceptable solder joints for both SMT and PTH components. It has been found that the Design for Manufacturability (DFM) guidelines, which were established for tin lead processes, in many cases do not result in the same level of quality joints when soldering with lead free alloy. Therefore, in order to improve the process yields and reduce manufacturing costs when converting to lead free, it is essential to establish DFM guidelines specifically for lead free soldering. The effect of pin to hole ratio, quantity of large copper planes connected to a pin through hole barrel, connection types for PTH and land patterns for glue and wave chip components are some of the main features which require further investigation for design optimization.

As there are a variety of lead free alloys available on the market today, each with differing properties, it is also important to determine if a set of DFM guidelines result in similar results among these various alloys.

This paper will discuss the outcome of a study of several DFM features incorporated on an internally designed test vehicle, which was created to evaluate alternative lead free alloys for Celestica. The DFM features included land pattern design and varying component spacing for chip components, pin to hole ratio and its interaction with the quantity of large copper planes connected to a PTH, quantity of large copper planes connected to a PTH and its interaction with the type of connection either solid or four spokes. The test vehicle was assembled with four Pb-free alloys (Sn-Cu-Ni, Sn-Ag-Cu-Bi, Sn-Cu-X & SAC405) and 63Sn-37Pb alloy as a baseline. The quality level of each of the described DFM features will be discussed. In addition to this, a detailed barrel fill analysis for the PTH components will be shown.

Mario Moreno, German Soto, Jessica Herrera, Teng Hoon Ng, Juthathip Fangkangwanwong Celestica Corporate (Toronto) , Celestica Mexico, Celestica Thailand

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Presenter: Craig Hamilton

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Authors: Ramon Mendez, Mario Moreno, German Soto,
Craig Hamilton

Background

It has been found that the Design for Manufacturability (DFM) guidelines for tin lead processes, in many cases do not result in the same quality level of solder joints when soldering with lead free alloys

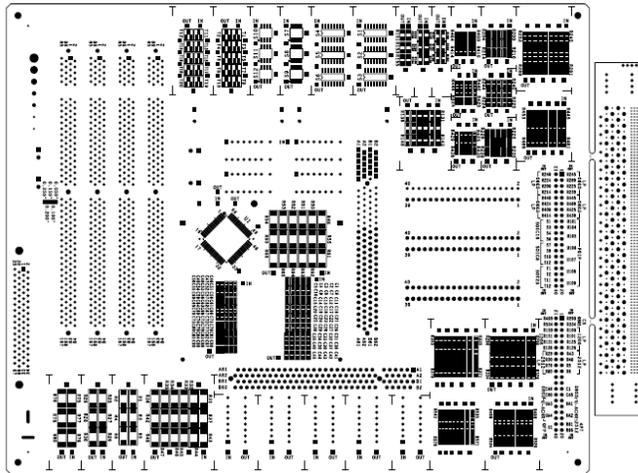
Objectives

- Evaluate the applicability of DFM guidelines established for SnPb in Pb-free process.
- Evaluate the performance of four Pb-free alloys through the DFM features studied.
- Set a reference to develop DFM guidelines for Pb-free wave soldering processes

Test Vehicle



Topside



Bottomside

- **Thickness:** 2.34mm (0.092")
- **Dimensions:** 203.2mm x 254mm (8" x 10")
- **Total Layers:** 12 layers
- **Ground Layers:** 4 layers (2oz Cu)
- **Surface Finish:** HighT OSP, Gliccoat F2LX
- **Laminate:** High Tg FR4, Polyclad 370HR
- **Solder Mask:** Taiyo PSR-4000
- **Mid Complexity PCB**
- **Daisy chained**

Components Used for DFM Analysis

| Component Type | Pin Count | Pitch | Lead finish |
|------------------------|-----------|--------|----------------------------|
| Power Connector | 40 | 2.54mm | Matte Tin over Nickel |
| DIMM Connector | 168 | 2.29mm | Gold over Palladium Nickel |
| 0805 Resistor | 2 | N/A | Tin over Nickel |
| 0603 Resistor | 2 | N/A | Tin over Nickel |
| 0805 Capacitor | 2 | N/A | Tin over Nickel |
| 0603 Capacitor | 2 | N/A | Tin |

Experimental Details

| ALLOYS | | MELTING RANGE |
|--|---------------|----------------|
| 95.5Sn-3.8Ag-0.7Cu | (SAC405) | 217°C to 220°C |
| 99.1Sn-0.7Cu-0.05Ni-(<0.01)Ge ¹ | (Sn-Cu-Ni) | 227°C |
| 99.1Sn-0.7Cu-X-Y | (Sn-Cu-X) | 227°C |
| 98.6Sn-0.3Ag-0.7Cu-Bi-X-Y ² | (Sn-Ag-Cu-Bi) | 217°C to 228°C |

| | | | |
|-------------|-----------------------------|------------|------------|
| Wave | Drilled Chip Bar and Lambda | | |
| Preheaters | | Top | Bottom |
| | Position 1 | IR | IR |
| | Position 2 | Convection | Convection |
| | Position 3 | | Convection |
| Atmosphere | Air | | |
| Fluxer | Selective Spray | | |
| Flux Volume | Supplier recommendation | | |

Machine Configuration

Process Optimization

DOE

| Factors | Levels | | |
|---------------------|--------|------|------|
| | 1 | 2 | 3 |
| Pot Temperature | Low | Med | High |
| Preheat Temperature | Low | High | |
| Contact Time | Low | High | |

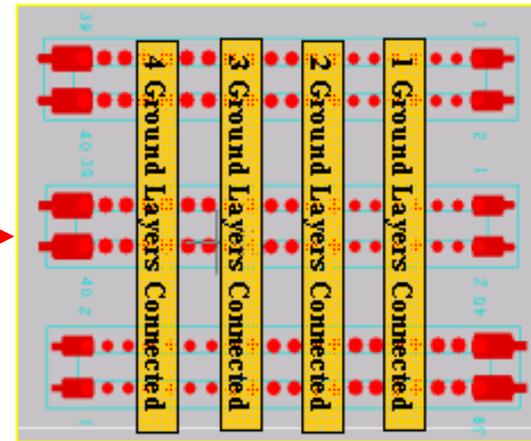
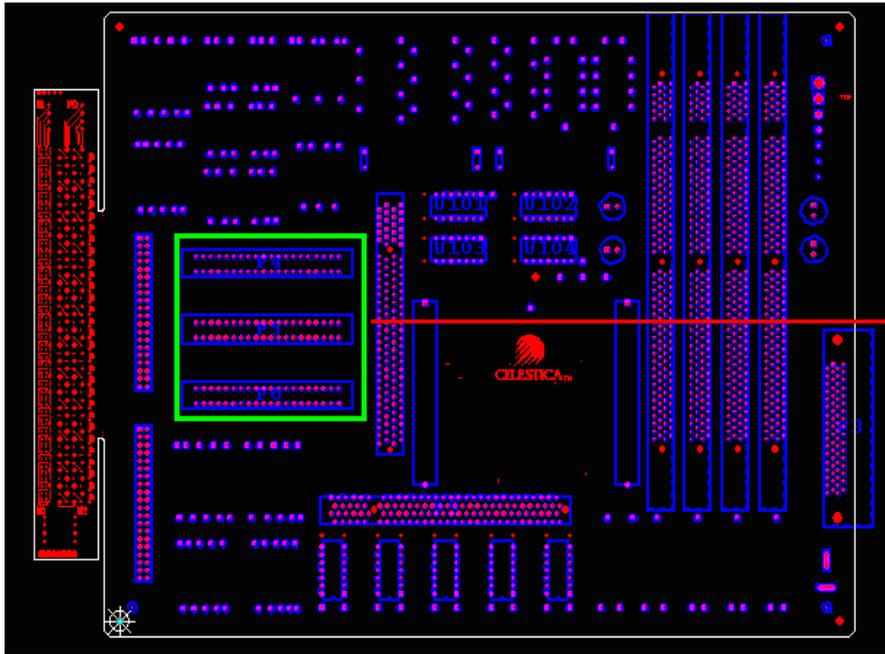


Optimal Setting

DFM Features

- Pin to hole ratio and qty. of large copper planes
- Quantity of large copper planes and PTH connection types
- Land pattern design
- Pad to pad spacing

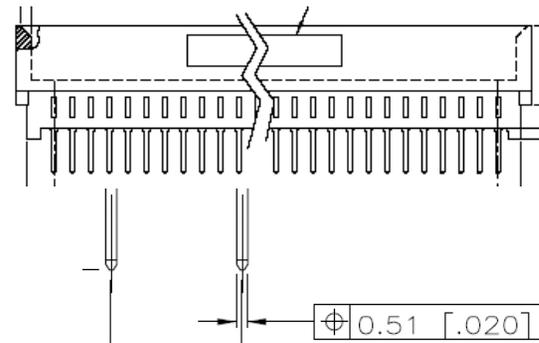
Pin to Hole Ratio and Large Copper Planes



| P2H Ratio |
|-----------|
| 0.71 |
| 0.63 |
| 0.60 |
| 0.57 |
| 0.56 |
| 0.50 |

Power Connector

**Lead Diameter = 0.508mm ± 0.127mm
0.020" ± 0.005"**



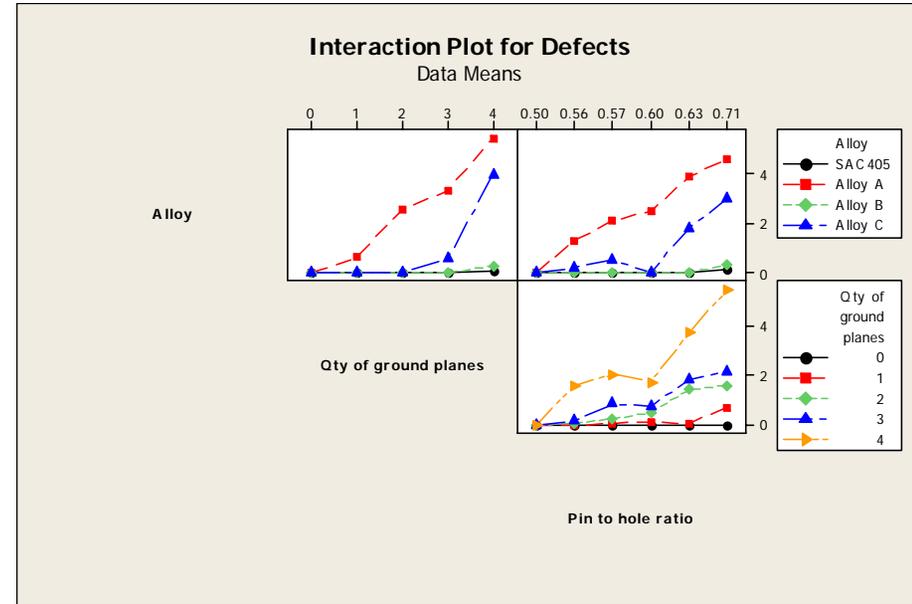
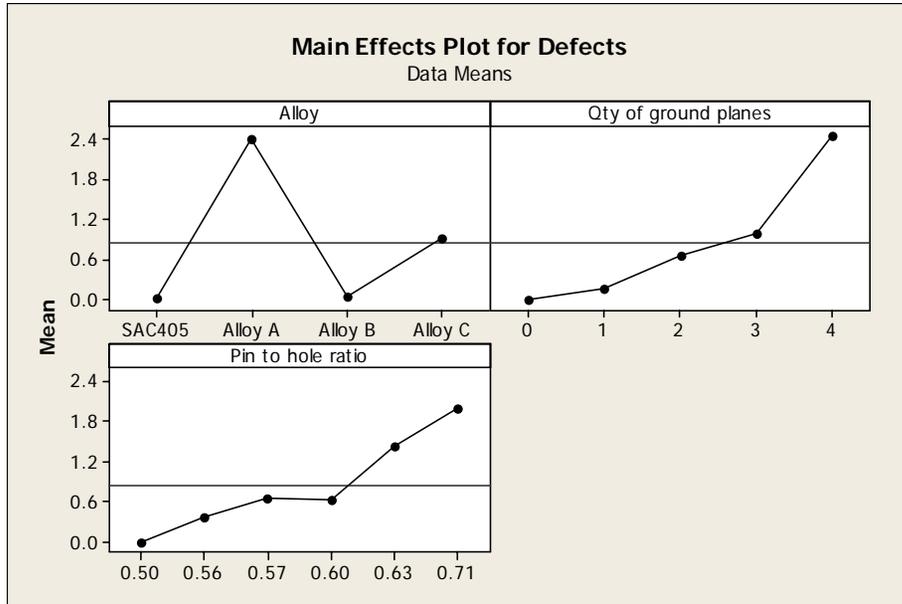
Pin to Hole Ratio and Large Copper Planes

- A Full Factorial, 3 Factors DOE was used:

| Factors | Levels | | | | | |
|---------------------------|--------|---------|---------|---------|------|------|
| | 1 | 2 | 3 | 4 | 5 | 6 |
| Alloy | SAC405 | Alloy A | Alloy B | Alloy C | | |
| Pin to Hole Ratio | 0.50 | 0.56 | 0.57 | 0.60 | 0.63 | 0.71 |
| Quantity of Ground Planes | 0 | 1 | 2 | 3 | 4 | |

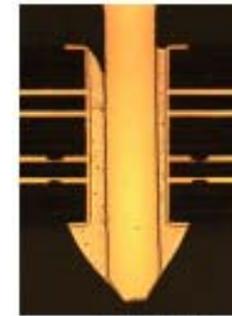
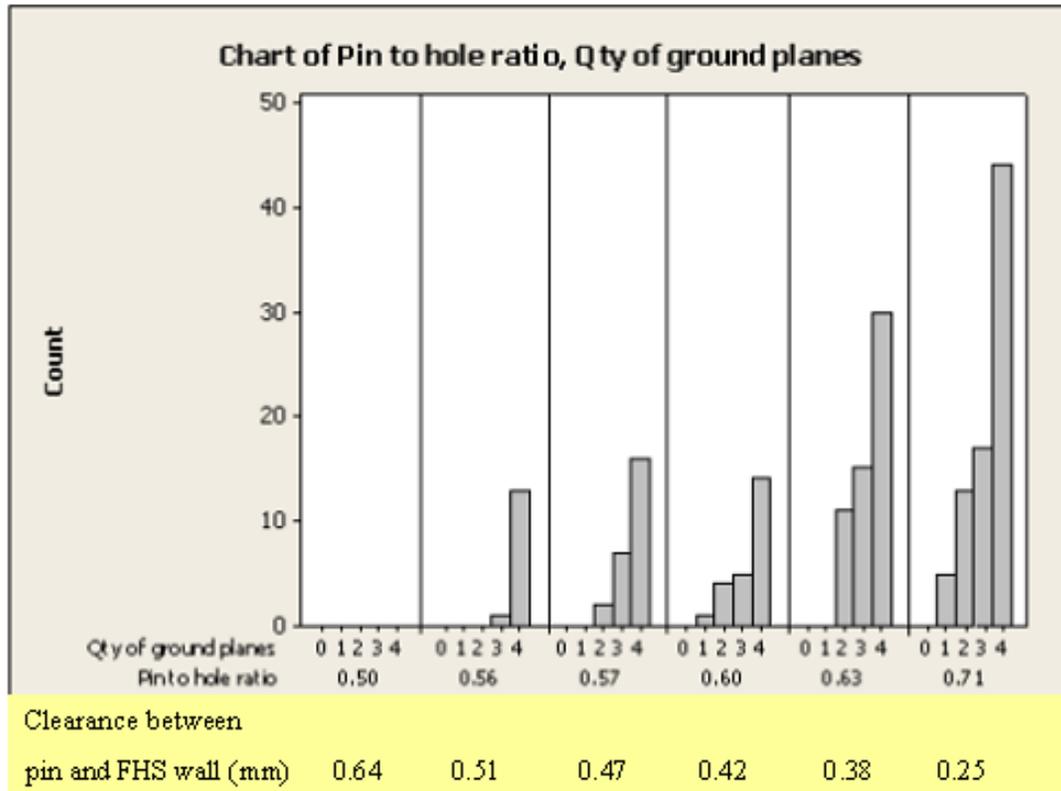
- **Response:** Barrel Fill Defects
- **Criteria:** IPC-A-610D Class 3

Pin to Hole Ratio and Large Copper Planes Results

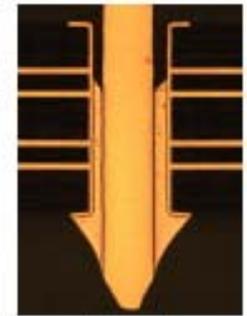


- Alloy B is statistically similar to SAC405
- Alloy A showed the higher quantity of defects followed by Alloy C
- The higher the quantity of ground planes, the higher the quantity of defects
- As the finished hole size decreases (higher pin to hole ratio), the quantity of defects increases.

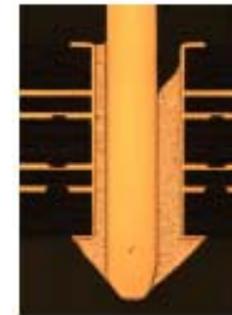
Pin to Hole Ratio and Large Copper Planes Results



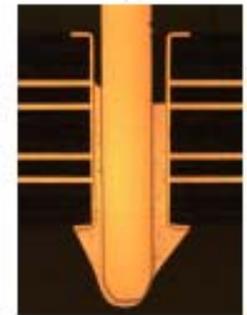
SAC405



Alloy A



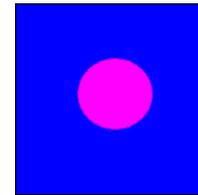
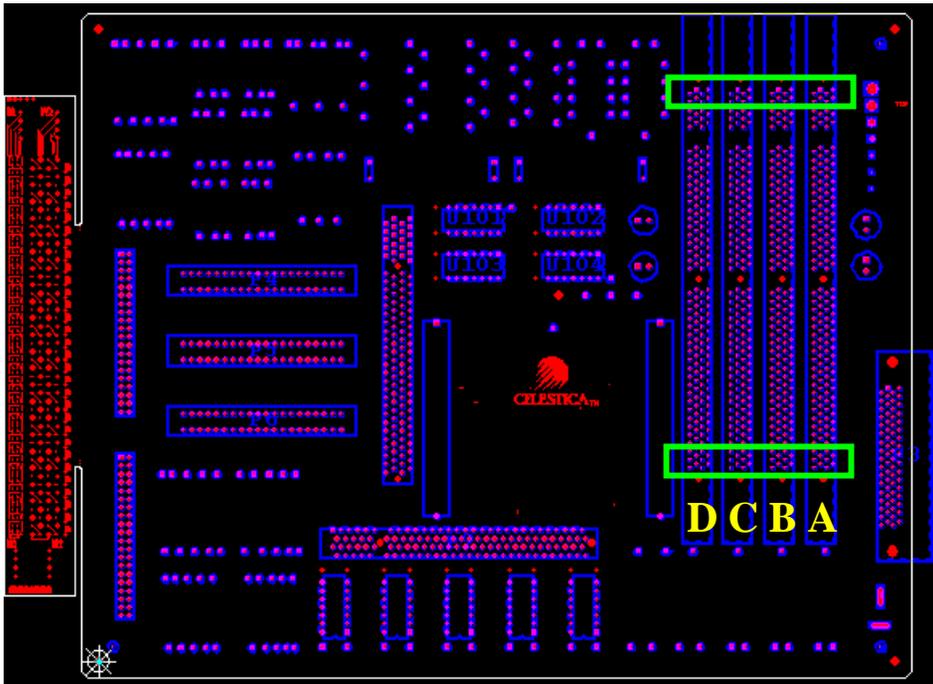
Alloy B



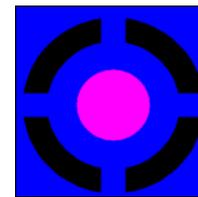
Alloy C

- Barrel fill improves with decreasing P2H ratio
- With no ground planes connected, there is no effect of P2H ratio on defects

Quantity of Large Copper Planes and PTH Connection Types



Solid Copper



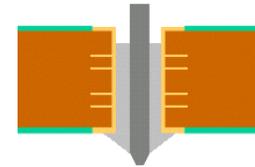
Four Spokes



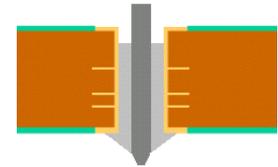
Drill



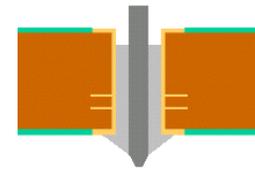
Copper



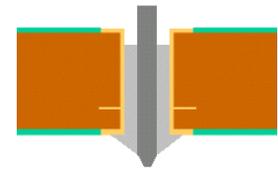
(A) 4 Ground planes



(B) 3 Ground planes



(C) 2 Ground planes



(D) 1 Ground plane

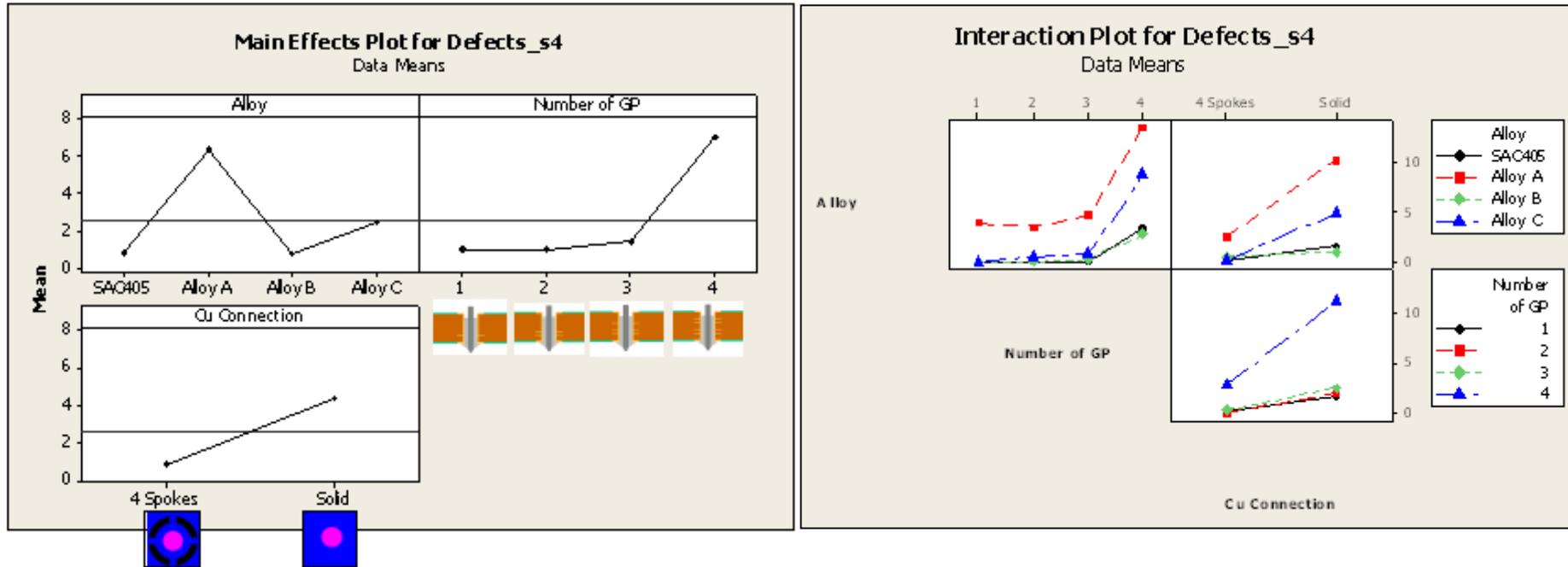
Quantity of Large Copper Planes and PTH Connection Types

- A Full Factorial, 3 Factors DOE was used:

| Factors | Levels | | | |
|---------------------------|----------|---------|---------|---------|
| | 1 | 2 | 3 | 4 |
| Alloy | SAC405 | Alloy A | Alloy B | Alloy C |
| Quantity of Ground Planes | 1 | 2 | 3 | 4 |
| Ground Connection Type | 4 spokes | Solid | | |

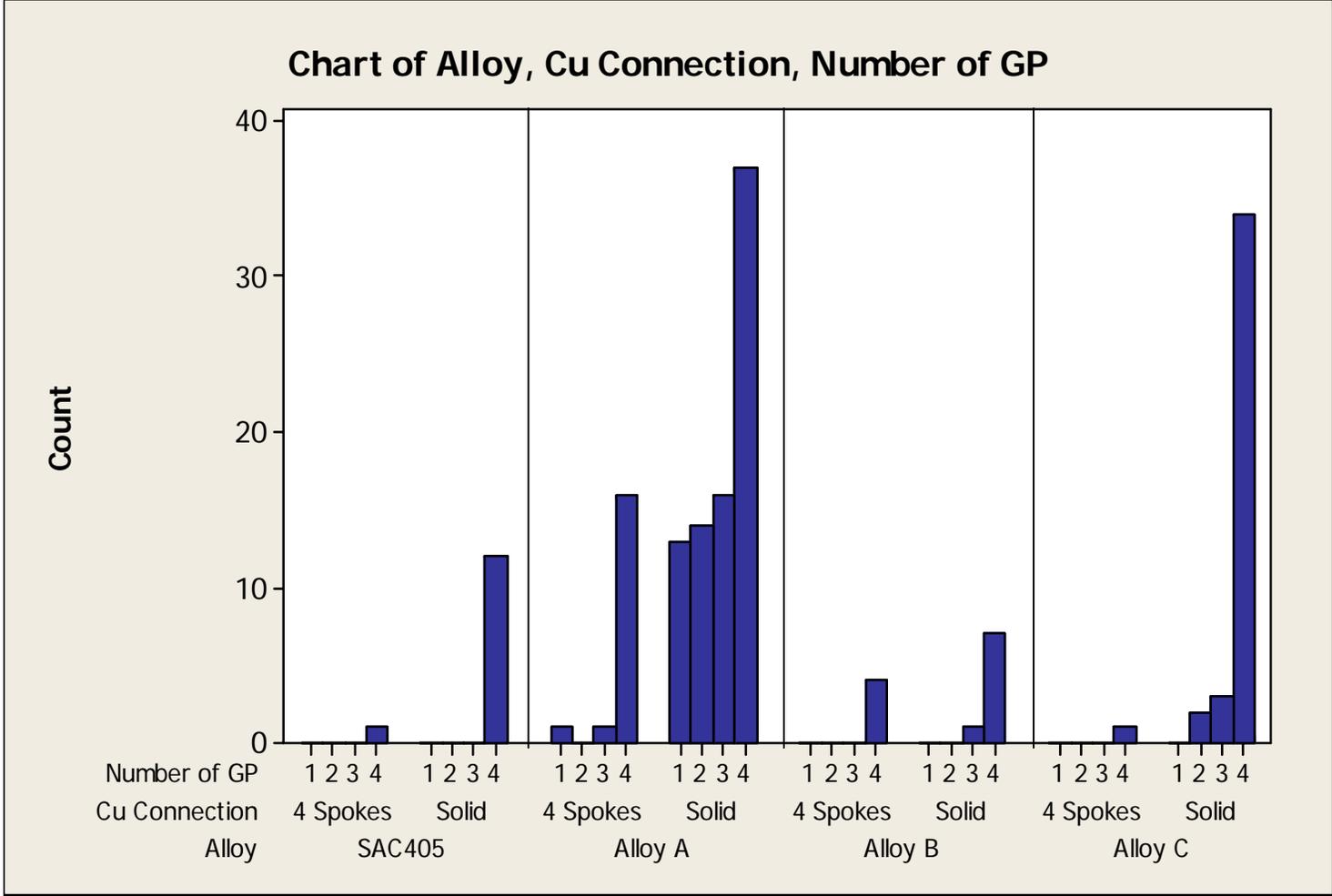
- **Response:** Barrel Fill Defects
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Quantity of Large Copper Planes and PTH Connection Types Results

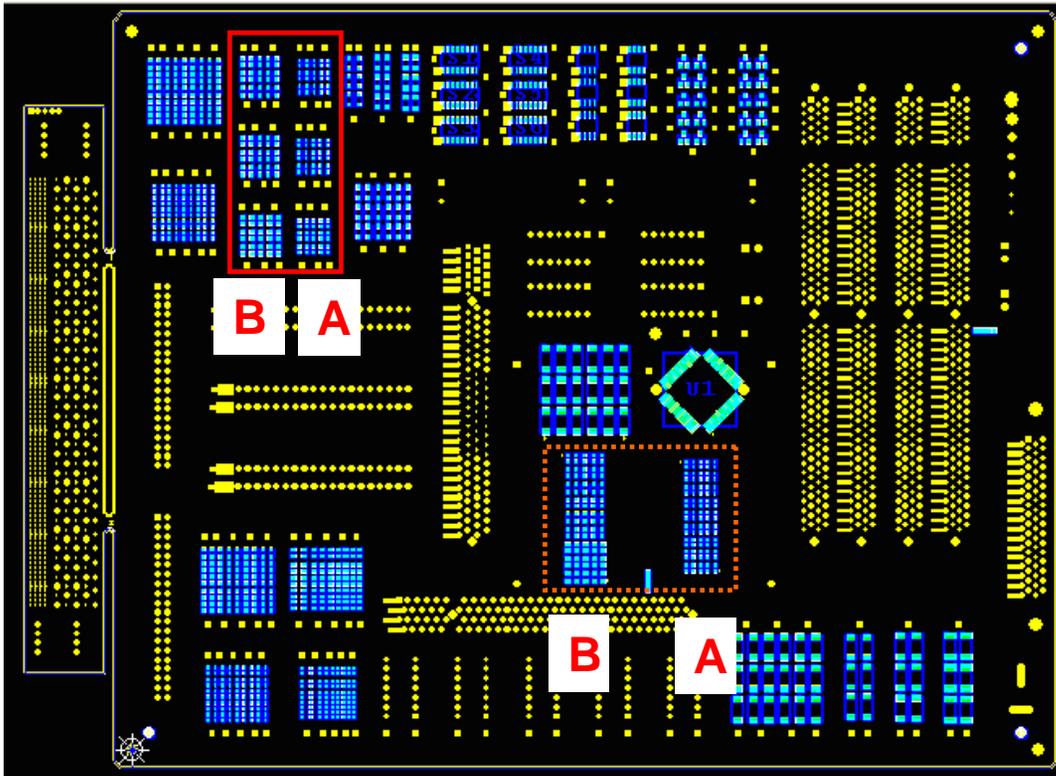


- Alloy A showed the higher quantity of defects followed by Alloy C, SAC405 and Alloy B performed the best
- With four ground planes the quantity of defects increases dramatically
- 4 spokes thermal relief helps to improve barrel fill, specially for 4 or more ground planes

Quantity of Large Copper Planes and PTH Connection Types Results



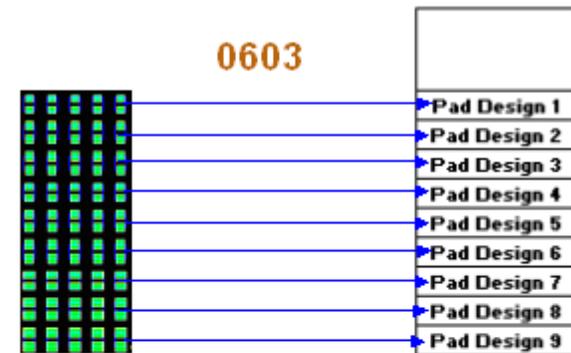
Land Pattern Design Variation



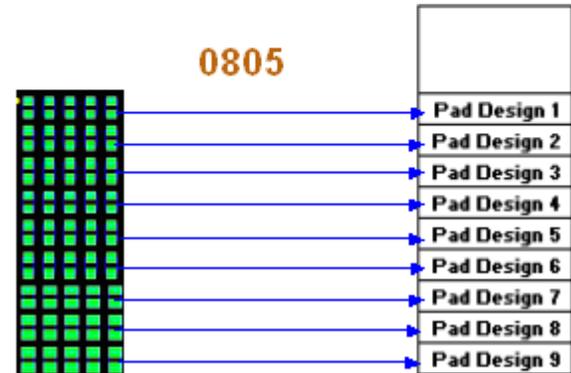
 Resistors

 Capacitors

A



B



Land Pattern Design Variation

DOE

| Pad Design | X | Y |
|------------|-------|--------|
| | Width | Length |
| 1 | Low | Low |
| 2 | Low | Med |
| 3 | Low | High |
| 4 | Med | Low |
| 5 | Med | Med |
| 6 | Med | High |
| 7 | High | Low |
| 8 | High | Med |
| 9 | High | High |

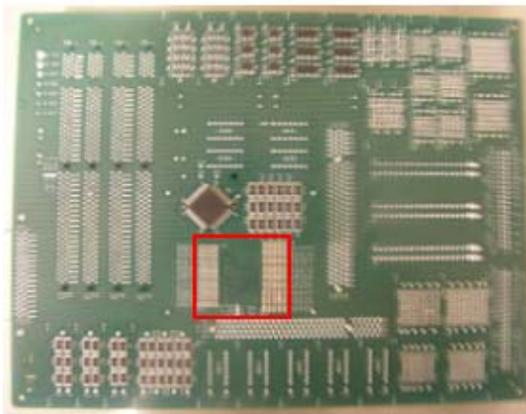
- X Low: Dimension below standard guideline for reflow pad design
- X Med: Dimension slightly below standard guideline for reflow pad design
- X High: Dimension at standard guideline for reflow pad design

- **Solders:** SAC405, SnPb and the three alternative alloys were evaluated
- **Response:** DPMO on Visual Inspection (Class 2, IPC-A-610D) and Maximum Shear Force

Land Pattern Design Variation

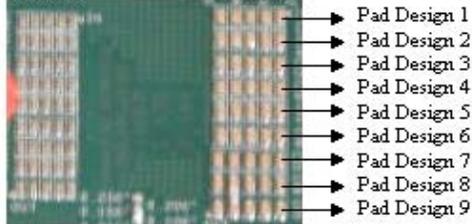
Shear Force Test

- SAC405, SnPb, Alloy A, Alloy B & Alloy C evaluated
- Five components of both 0805 and 0603 were tested for each of the 9 land pattern designs
- ASTM F1269 standard followed



0603

0805

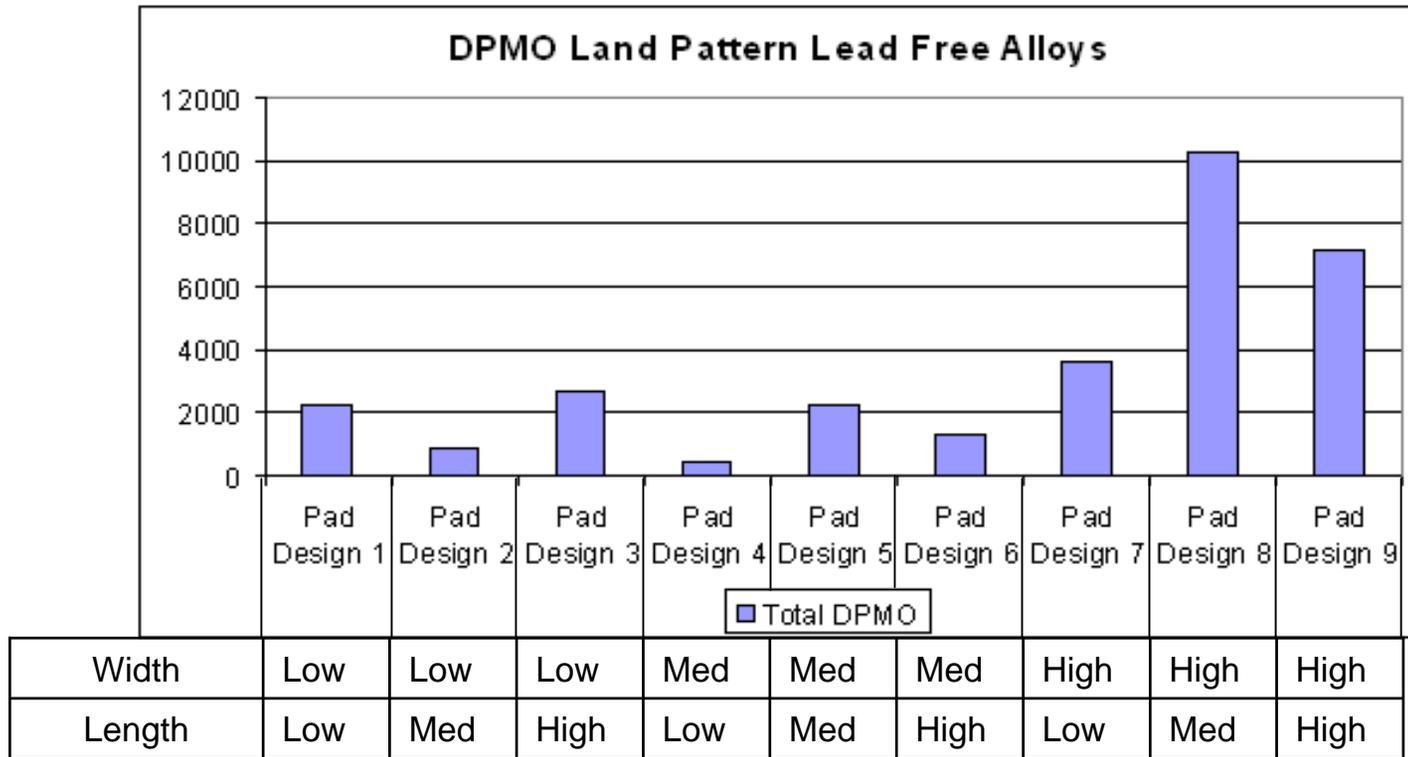


| Alloy | Land pattern design | Component | Sample Size |
|---|---------------------|-----------|-------------|
| SnPb SAC405 Alloy A Alloy B Alloy C | 1 | 0603 | 5 |
| | | 0805 | 5 |
| | 2 | 0603 | 5 |
| | | 0805 | 5 |
| | 3 | 0603 | 5 |
| | | 0805 | 5 |
| | 4 | 0603 | 5 |
| | | 0805 | 5 |
| | 5 | 0603 | 5 |
| | | 0805 | 5 |
| | 6 | 0603 | 5 |
| | | 0805 | 5 |
| | 7 | 0603 | 5 |
| | | 0805 | 5 |
| | 8 | 0603 | 5 |
| | | 0805 | 5 |
| | 9 | 0603 | 5 |
| | | 0805 | 5 |



Land Pattern Design Results

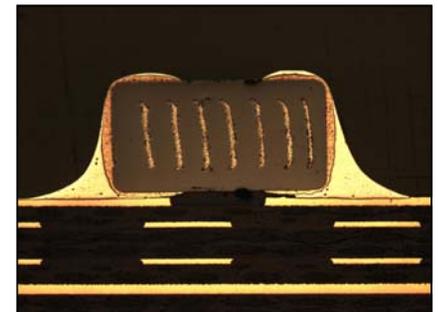
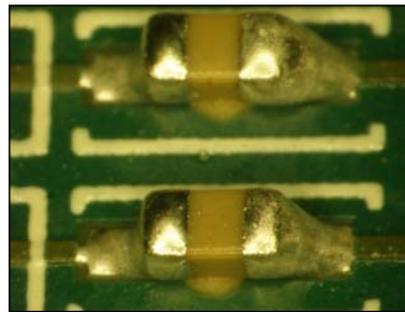
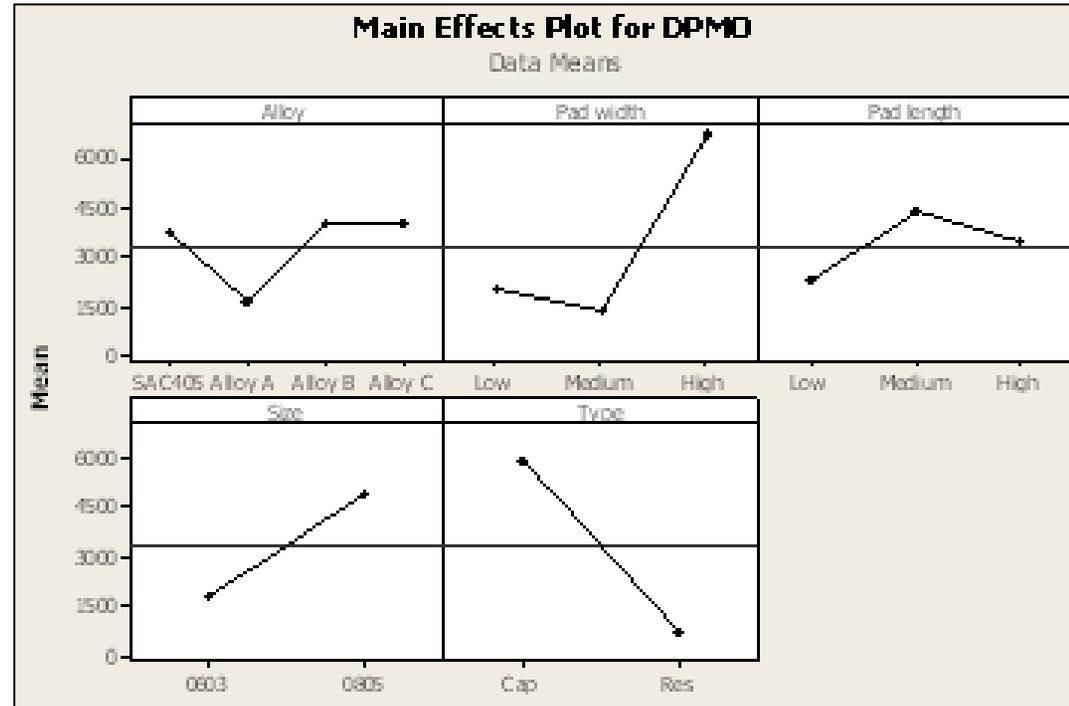
Combined results for the 9 different land patterns (0603 and 0805)



- Land pattern designs 7, 8 and 9 (widest pad) have the higher quantity of defects
- Pad designs 4 and 2 performed the best

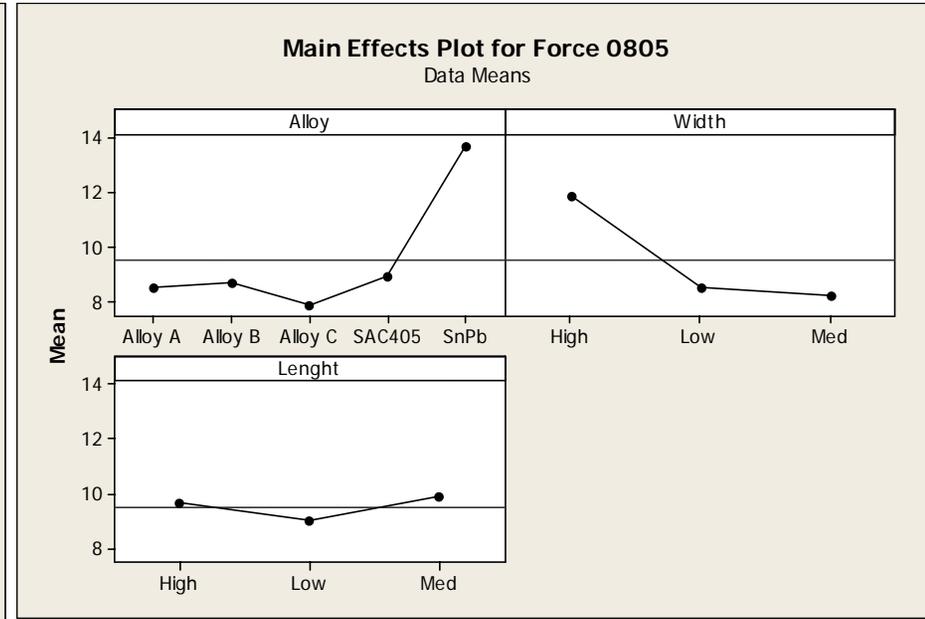
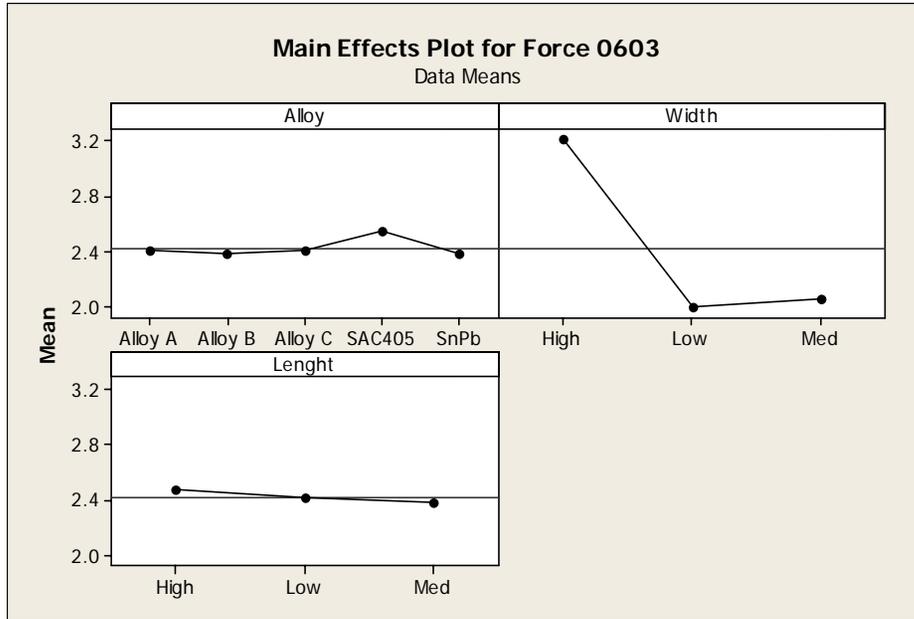
Land Pattern Design Results

- Best Pad width is the medium level (slightly lower than pad width used for reflow)
- Pad lengths used were statistically similar
- 0603 capacitors and resistors deliver the lowest defect count
- Alloys B, C and SAC405 performed statistically at the same level. Alloy A performed the best



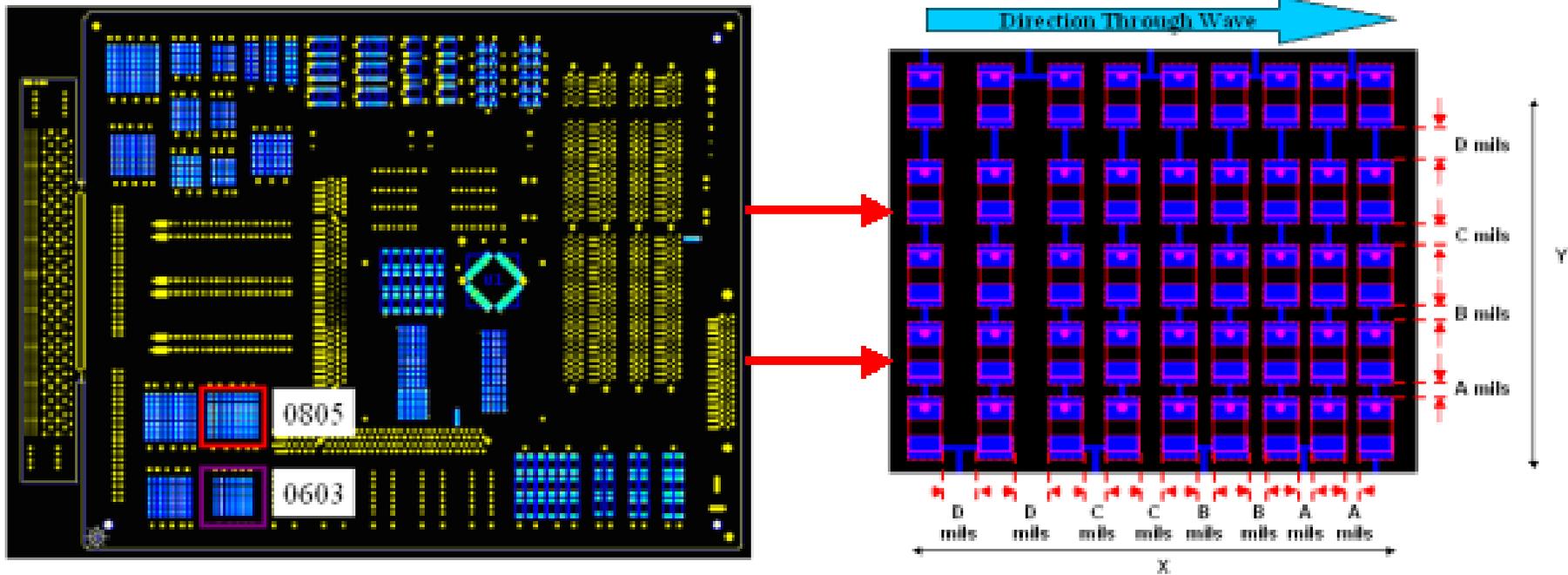
Land Pattern Design Results

Shear Force Test



- High width levels provided the largest strength for both, 0603 and 0805
- 0805 strength larger than 0603 due to more contact area for the solder joint
- SnPb behaves statistically similar than SAC alloys for 0603 component
- For 0805 component, SnPb is the alloy with the higher strength.

Pad to Pad Spacing Variation



- 0805 and 0603 components tested
- Four distances used on the X and Y axis

Pad to Pad Spacing Variation

- A Full Factorial, 3 Factors DOE was used:

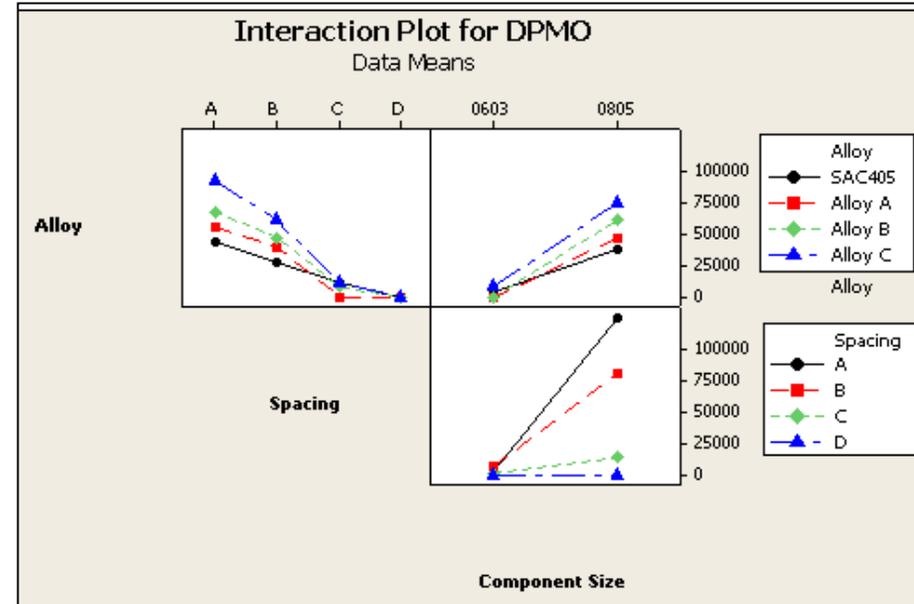
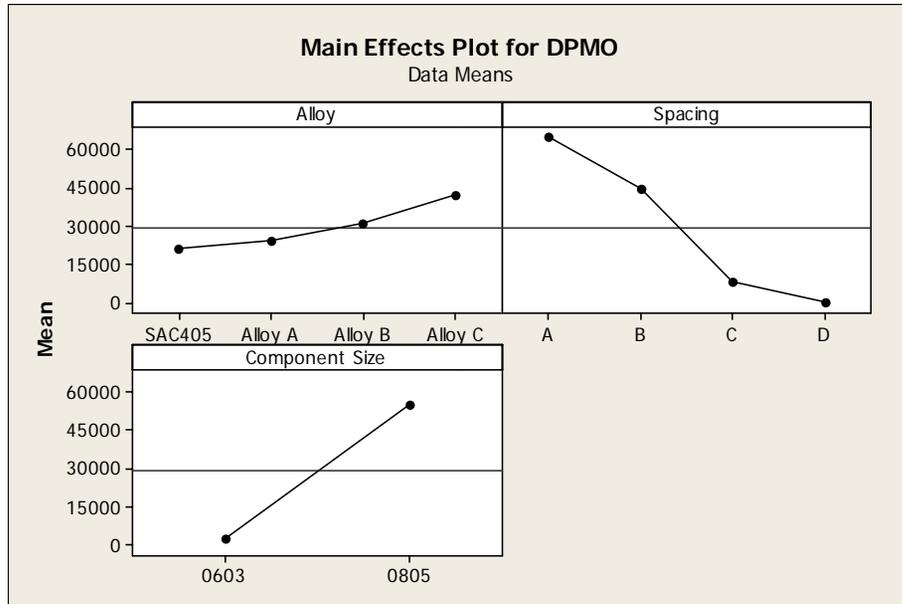
DOE

| Alloy | Component | |
|---------|-----------|------|
| | 0603 | 0805 |
| SAC405 | A | A |
| | B | B |
| | C | C |
| | D | D |
| Alloy A | A | A |
| | B | B |
| | C | C |
| | D | D |
| Alloy B | A | A |
| | B | B |
| | C | C |
| | D | D |
| Alloy C | A | A |
| | B | B |
| | C | C |
| | D | D |

A: Spacing slightly below 0.64mm
B: 0.64 mm (**0.025"**)
C: Spacing slightly above 0.64mm
D: Spacing above 0.64mm (**0.025"**)

- Response: DPMO on Visual Inspection (Class 3, IPC-A-610D)

Pad to Pad Spacing Variation Results



- **SAC405 performed the best followed closely by Alloy A**
- **0603 components show a lower quantity of defects among the 4 different spacing used**
- **With spacing A (0.5mm) and spacing B (0.64mm) the quantity of defects increased a lot**

Conclusions

| | | |
|--|---|--|
| Pin to Hole Ratio | <p>P2H ratio between 0.50 & 0.60 (equivalent to a clearance of 0.64 mm to 0.42 mm) is recommended</p> <p>May not apply for larger pin areas</p> | |
| Ground Planes (from 0 to 4 used) | <p>3 or less ground planes are recommended when using four spokes thermal relief and the P2H ratios mentioned above</p> | |
| PTH Connection Types | <p>Recommend incorporating 4 spokes thermal relief to minimize barrel fill defects. This recommendation takes more relevance as the quantity of ground planes increases</p> | |
| Land Pattern Design | <p><u>Visual Inspection</u></p> <p>Pad Width slightly below reflow design standard is recommended</p> <p>Pad Length doesn't affect</p> | <p><u>Shear Force</u></p> <p>Shear Force increases with increasing pad width</p> <p>No statistical difference for 0603 components among SnPb and LF Alloys</p> |
| Pad to Pad Spacing | <p>Recommend having distances higher than 0.64mm to minimize solder bridges</p> | |
| Alloys | <p>Alloy B resulted as the more robust Pb-free alloy among the three alternatives, performing very similar to the SAC405</p> | |